

December 1994

54F/74F153 Dual 4-Input Multiplexer

General Description

The 'F153 is a high-speed dual 4-input multiplexer with common select inputs and individual enable inputs for each section. It can select two lines of data from four sources. The two buffered outputs present data in the true (non-inverted)

form. In addition to multiplexer operation, the 'F153 can generate any two functions of three variables.

Features

■ Guaranteed 4000V minimum ESD protection

Commercial	Military	Package Number	Package Description		
74F153PC		N16E	16-Lead (0.300" Wide) Molded Dual-In-Line		
	54F153DM (Note 2)	J16A	16-Lead Ceramic Dual-In-Line		
74F153SC (Note 1)		M16A	16-Lead (0.150" Wide) Molded Small Outline, JEDEC		
74F153SJ (Note 1)		M16D	16-Lead (0.300" Wide) Molded Small Outline, EIAJ		
	54F153FM (Note 2)	W16A	16-Lead Cerpack		
	54F153LM (Note 2)	E20A	20-Lead Ceramic Leadless Chip Carrier, Type C		

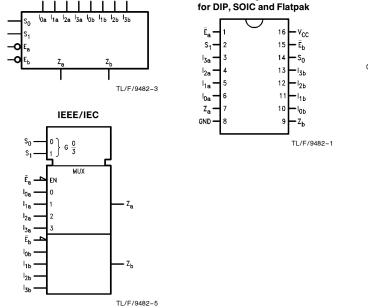
Pin Assignment

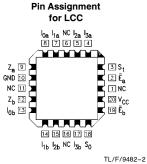
Note 1: Devices also available in 13" reel. Use suffix = SCX and SJX.

Note 2: Military grade device with environmental and burn-in processing. Use suffix = DMQB, FMQB and LMQB.

Logic Symbols

Connection Diagrams





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Unit Loading/Fan Out

		54F/74F			
Pin Names	Description	U.L. HIGH/LOW	Input I _{IH} /I _{IL} Output I _{OH} /I _{OL}		
I _{0a} -I _{3a}	Side A Data Inputs	1.0/1.0	20 μA/-0.6 mA		
I _{0b} -I _{3b}	Side B Data Inputs	1.0/1.0	20 μA/ – 0.6 mA		
S ₀ , S ₁	Common Select Inputs	1.0/1.0	20 μA/ – 0.6 mA		
Ē _a	Side A Enable Input (Active LOW)	1.0/1.0	20 μA/ – 0.6 mA		
Ēb	Side B Enable Input (Active LOW)	1.0/1.0	20 μA/ – 0.6 mA		
Za	Side A Output	50/33.3	-1 mA/20 mA		
Z _b	Side B Output	50/33.3	-1 mA/20 mA		

Functional Description

The 'F153 is a dual 4-input multiplexer. It can select two bits of data from up to four sources under the control of the common Select inputs (S₀, S₁). The two 4-input multiplexer circuits have individual active LOW Enables (\overline{E}_a , \overline{E}_b) which can be used to strobe the outputs independently. When the Enables $(\overline{E}_a, \overline{E}_b)$ are HIGH, the corresponding outputs $(Z_a,$ Z_b) are forced LOW. The 'F153 is the logic implementation of a 2-pole, 4-position switch, where the position of the switch is determined by the logic levels supplied to the two Select inputs. The logic equations for the outputs are as follows:

$$\begin{split} Z_{a} &= \overline{E}_{a} \bullet (I_{0a} \bullet \overline{S}_{1} \bullet \overline{S}_{0} \, + \, I_{1a} \bullet \overline{S}_{1} \bullet S_{0} \, + \\ & I_{2a} \bullet S_{1} \bullet \overline{S}_{0} \, + \, I_{3a} \bullet S_{1} \bullet S_{0}) \\ Z_{b} &= \overline{E}_{b} \bullet (I_{0b} \bullet \overline{S}_{1} \bullet \overline{S}_{0} \, + \, I_{1b} \bullet \overline{S}_{1} \bullet S_{0} \, + \\ & I_{2b} \bullet S_{1} \bullet \overline{S}_{0} \, + \, I_{3b} \bullet S_{1} \bullet S_{0}) \end{split}$$

The 'F153 can be used to move data from a group of registers to a common output bus. The particular register from which the data came would be determined by the state of the Select inputs. A less obvious application is as a function generator. The 'F153 can generate two functions of three variables. This is useful for implementing highly irregular random logic.

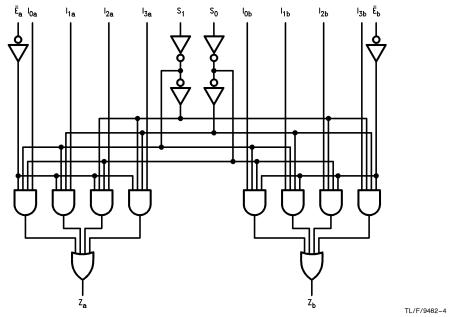
Truth Table

	lect outs		Output				
S ₀	S ₁	Ē	I ₀	l ₁	l ₂	l ₃	Z
Х	Х	Н	Х	Х	Х	Х	L
L	L	L	L	Χ	Χ	Х	L
L	L	L	Н	Χ	Χ	Х	Н
Н	L	L	Х	L	Χ	Х	L
Н	L	L	Х	Н	Χ	Х	Н
L	Н	L	Х	Χ	L	Х	L
L	Н	L	X	Χ	Н	Х	Н
Н	Н	L	Х	Χ	Χ	L	L
Н	Н	L	X	X	X	Н	Н

 $\begin{array}{ll} H = \mbox{HIGH Voltage Level} \\ L = \mbox{LOW} \end{array}$

X = Immaterial

Logic Diagram



Please note that this diagram is provided only for the understanding of logic operations and should not be used to estimate propagation delays.

Absolute Maximum Ratings (Note 1)

If Military/Aerospace specified devices are required, please contact the National Semiconductor Sales Office/Distributors for availability and specifications.

 $\begin{array}{lll} \mbox{Storage Temperature} & -65^{\circ}\mbox{C to} + 150^{\circ}\mbox{C} \\ \mbox{Ambient Temperature under Bias} & -55^{\circ}\mbox{C to} + 125^{\circ}\mbox{C} \\ \mbox{Junction Temperature under Bias} & -55^{\circ}\mbox{C to} + 175^{\circ}\mbox{C} \\ \mbox{Plastic} & -55^{\circ}\mbox{C to} + 150^{\circ}\mbox{C} \\ \end{array}$

V_{CC} Pin Potential to

 Ground Pin
 −0.5V to +7.0V

 Input Voltage (Note 2)
 −0.5V to +7.0V

 Input Current (Note 2)
 −30 mA to +5.0 mA

Voltage Applied to Output

in HIGH State (with $V_{CC} = 0V$)

 $\begin{array}{ll} \mbox{Standard Output} & -0.5\mbox{V to V}_{\mbox{CC}} \\ \mbox{TRI-STATE} \mbox{$^{\circ}$ Output} & -0.5\mbox{V to } +5.5\mbox{V} \end{array}$

Current Applied to Output

in LOW State (Max) twice the rated I_{OL} (mA)

Note 1: Absolute maximum ratings are values beyond which the device may be damaged or have its useful life impaired. Functional operation under these conditions is not implied.

Note 2: Either voltage limit or current limit is sufficient to protect inputs.

Recommended Operating Conditions

Free Air Ambient Temperature

Supply Voltage

Military +4.5V to +5.5V Commercial +4.5V to +5.5V

DC Electrical Characteristics

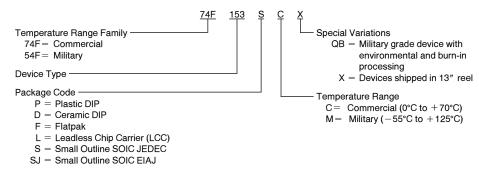
Symbol	Parameter		54F/74F			Units	Vcc	Conditions	
Oymboi			Min	Тур	Max	Onits	VCC	Conditions	
V_{IH}	Input HIGH Voltage		2.0			V		Recognized as a HIGH Signa	
V _{IL}	Input LOW Voltage			0.8	V		Recognized as a LOW Signal		
V _{CD}	Input Clamp Diode Vo	oltage			-1.2	٧	Min	$I_{\text{IN}} = -18 \text{mA}$	
V _{OH}	Output HIGH Voltage	54F 10% V _{CC} 74F 10% V _{CC} 74F 5% V _{CC}	2.5 2.5 2.7			V	Min	$I_{OH} = -1 \text{ mA}$ $I_{OH} = -1 \text{ mA}$ $I_{OH} = -1 \text{ mA}$	
V _{OL}	Output LOW Voltage	54F 10% V _{CC} 74F 10% V _{CC}			0.5 0.5	٧	Min	$I_{OL} = 20 \text{ mA}$ $I_{OL} = 20 \text{ mA}$	
lін	Input HIGH Current	54F 74F			20.0 5.0	μΑ	Max	$V_{IN} = 2.7V$	
I _{BVI}	Input HIGH Current Breakdown Test	54F 74F			100 7.0	μΑ	Max	$V_{IN} = 7.0V$	
I _{CEX}	Output High Leakage Current	54F 74F			250 50	μΑ	Max	$V_{OUT} = V_{CC}$	
V_{ID}	Input Leakage Test	74F	4.75			٧	0.0	$I_{\text{ID}} = 1.9 \mu\text{A}$ All Other Pins Grounded	
l _{OD}	Output Leakage Circuit Current	74F			3.75	μΑ	0.0	V _{IOD} = 150 mV All Other Pins Grounded	
I _{IL}	Input LOW Current				-0.6	mA	Max	V _{IN} = 0.5V	
los	Output Short-Circuit 0	-60		-150	mA	Max	V _{OUT} = 0V		
Iccl	Power Supply Curren		12	20	mA	Max	$V_O = LOW$		

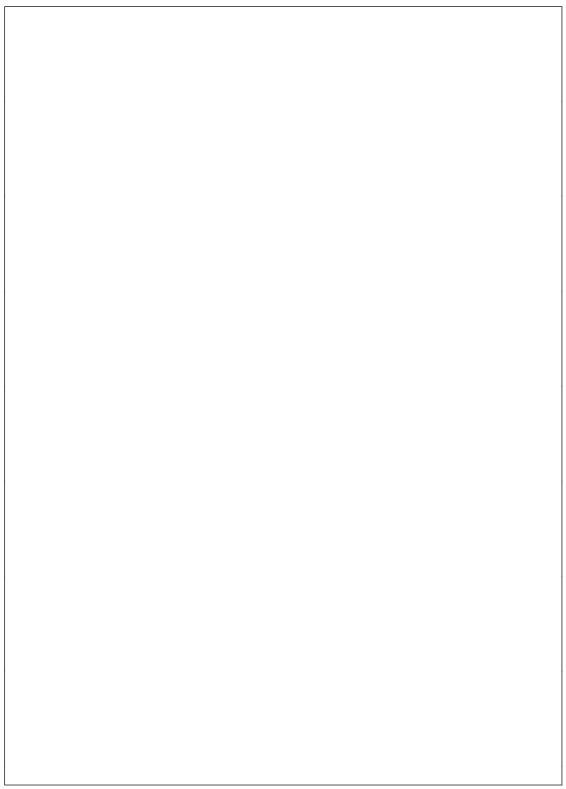
AC Electrical Characteristics

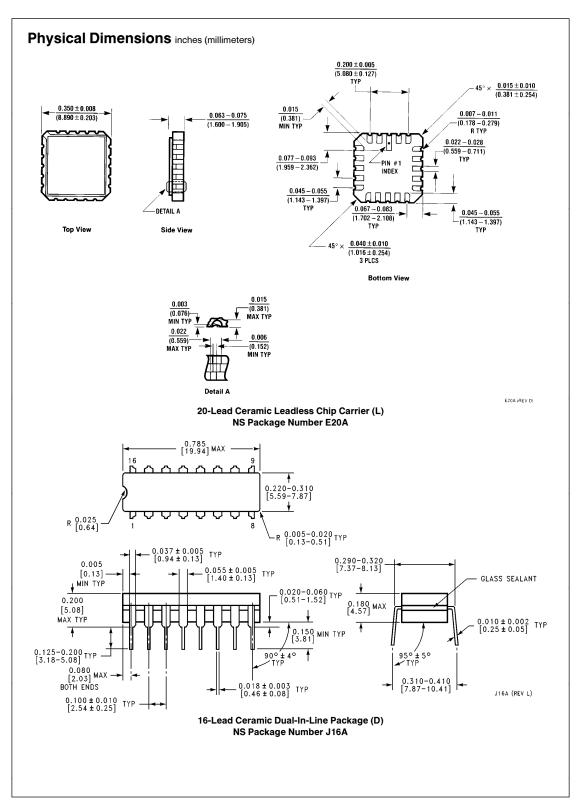
Symbol	Parameter	$ \begin{array}{c} {\it T_{A}} = + 25^{\circ}{\it C} \\ {\it V_{CC}} = + 5.0{\it V} \\ {\it C_{L}} = 50 {\it pF} \end{array} $			54F T _A , V _{CC} = Mil C _L = 50 pF		74F T _A , V _{CC} = Com C _L = 50 pF		Units	
		Min	Тур	Max	Min	Max	Min	Max		
t _{PLH} t _{PHL}	Propagation Delay S _n to Z _n	4.5 3.5	8.1 7.0	10.5 9.0	4.5 3.5	14.0 11.0	4.5 3.5	12.0 10.5	ns	
t _{PLH}	Propagation Delay \overline{E}_n to Z_n	4.5 3.0	7.1 5.7	9.0 7.0	4.5 2.5	11.5 9.0	4.5 2.5	10.5 8.0	ns	
t _{PLH}	Propagation Delay I _n to Z _n	3.0 2.5	5.3 5.1	7.0 6.5	2.5 2.5	9.0 8.0	3.0 2.5	8.0 7.5	ns	

Ordering Information

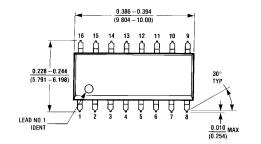
The device number is used to form part of a simplified purchasing code where the package type and temperature range are defined as follows:

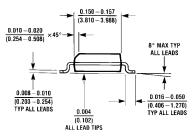


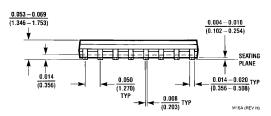




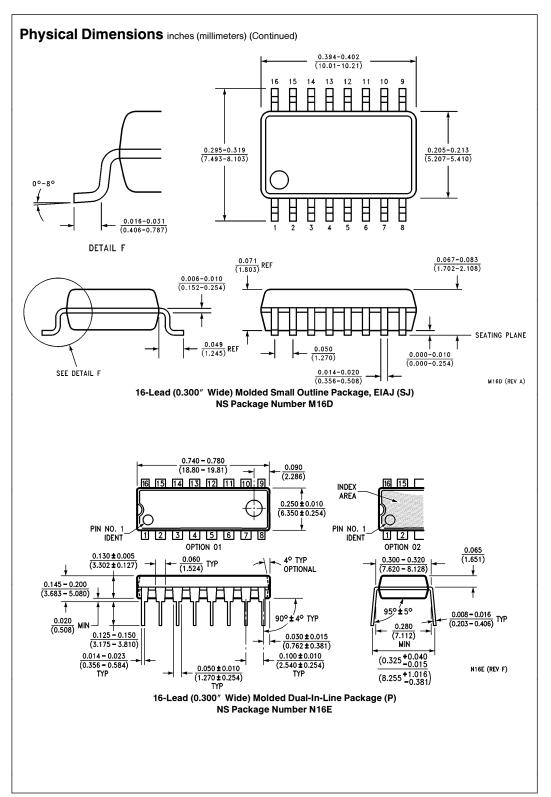




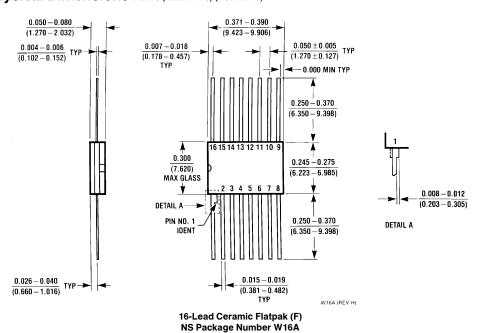




16-Lead (0.150" Wide) Molded Small Outline Package, JEDEC (S) NS Package Number M16A



Physical Dimensions inches (millimeters) (Continued)



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